

WAFER DATASHEET

Features

- Power MOSFET
- Low Gate Charge
- Excellent $R_{DS(ON)}$

Applications

- Load Switch, Motor Driving
- DC-DC Converters
- Power Management Functions



Device Symbol

Chip Information

Parameter	Value
Die Size (include scribe line)	741 μm $\times$ 800 μm
Gate Pad Size	135 μm $\times$ 135 μm
Source Pad Size	Full Opening Area
Scribe Line Size	60 μm
Wafer Thickness	150 μm $\pm$ 15 μm
Wafer Diameter	200 mm
Front Metal Composition & Thickness	AlCu, 4 μm
Back Metal Composition & Thickness	Ti-Ni-Ag, 1k $\text{\AA}$ -2k $\text{\AA}$ -10k $\text{\AA}$
Passivation	SRO 6k $\text{\AA}$ + SiN 5k $\text{\AA}$
Polyimide	NA
Gross Die (approximately)	100,000 (50,000 $\times$ 2)

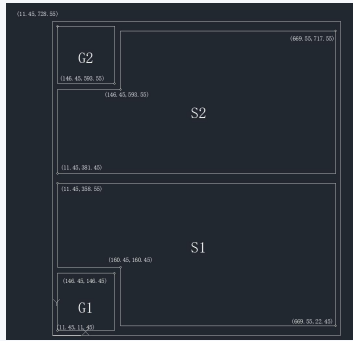


Diagram of chip

Maximum Ratings (@ $T_A = 25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Units
Drain – Source Voltage	V_{DS}	20	V
Gate – Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	6	A
Junction Temperature Range	T_J	$-55 \sim +150$	$^\circ\text{C}$

Electrical Characteristics (@ $T_A = 25^\circ\text{C}$, unless otherwise specified.)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Off Characteristics						
Drain–Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	20	—	—	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}, T_J = 25^\circ\text{C}$	—	—	1.0	μA
Gate–Body Leakage Current	I_{GSS}	$V_{GS} = \pm 12\text{ V}, V_{DS} = 0\text{ V}$	—	—	± 100	nA
On Characteristics ⁽¹⁾						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\text{ }\mu\text{A}$	0.4	0.6	0.9	V
Static Drain–Source On-Resistance ^(FT)	$R_{DS(ON)}$	$V_{GS} = 4.5\text{ V}, I_D = 4\text{ A}$	—	21	25.0	m Ω
		$V_{GS} = 2.5\text{ V}, I_D = 3\text{ A}$	—	26	30.0	m Ω
Static Drain–Source On-Resistance ^(CP)	$R_{DS(ON)}$	$V_{GS} = 4.5\text{ V}, I_D = 1\text{ A}$	—	—	25.0	m Ω
		$V_{GS} = 2.5\text{ V}, I_D = 1\text{ A}$	—	—	30.0	m Ω
Diode Forward Voltage	V_{SD}	$I_S = 2.0\text{ A}, V_{GS} = 0\text{ V}$	—	0.7	1.0	V

Notes

1. Measured under pulsed conditions. Pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
2. $R_{DS(ON)}$ value is referred by the device assembled in SOT26.

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